CLAIM AMENDMENTS

1. (Currently Amended) An interconnecting structure comprising: first wirings formed on a substrate;

a low-k dielectric film formed on the first wirings, the low-k dielectric film having a dielectric constant of not exceeding 3 or less;

vias formed in the low-k dielectric film and connected to the first wiring; second wirings formed on the vias and connected to the vias; and dummy vias formed on the periphery of an isolated via of the vias.

- 2. (Currently Amended) The interconnecting structure according to claim 1, further comprising a cap film formed on the low-k dielectric film, wherein the second wiring is wirings are formed in the cap film and the low-k dielectric film.
- 3. (Currently Amended) The interconnecting structure according to claim 1, further comprising:

first dummy wirings formed on the periphery of the first wirings; and second dummy wirings formed on the periphery of the second wirings, wherein the dummy vias are is connected to the first and second dummy wirings, and one of the first or and second dummy wirings connected to the dummy vias are connected to a ground potential.

- 4. (Original) The interconnecting structure according to claim 1, wherein the dummy vias have a slit shape.
- 5. (Currently Amended) The interconnecting structure according to claim 1, wherein the dimension of the dummy vias—is have a dimension 1 to 10 times the a minimum dimension of the vias.